

**AMENDMENTS TO THE SPECIFICATION:****On page 1 after the title, please insert the following:****--RELATED APPLICATIONS**

The present application is based on, International Application No. PCT/FR03/00987, filed on March 28, 2003, entitled "DEVICE FOR MEASURING THE EMISSION OF X-RAYS PRODUCED BY AN OBJECT EXPOSED TO AN ELECTRON BEAM", which in turn corresponds to French Application No. FR 02 04074 filed on March 29, 2002, and priority is hereby claimed under 35 USC 119 based on these applications. Each of these applications are hereby incorporated by reference herein in its entirety.

**FIELD OF THE INVENTION--****On page 1 after line 15, please insert the following header:****--BACKGROUND OF THE INVENTION --****On page 3 top of page (first line) please insert the following header:****--SUMMARY OF THE INVENTION --****On page 3 after line 33, please enter the following header:****--BRIEF DESCRIPTION OF THE DRAWING--****On page 4 after line 6, please insert the following header:****--DETAILED DESCRIPTION OF THE INVENTION --**